

DETAILED ACTION

EXAMINER'S AMENDMENT

1. An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it **MUST** be submitted no later than the payment of the issue fee.

Authorization for this examiner's amendment was given in a telephone interview with Mr. Webb Hunter on 10/17/2008. Claims 1 and 21-22 have been amended as follows:

1. A system for matching one or more abbreviations and one or more definitions, comprising:

a recognition process that examines character strings and determines which character strings to be abbreviated;

an abbreviation pattern generation process that creates from said determined character strings one or more abbreviation patterns representing candidate abbreviations, each of the one or more abbreviation patterns being a template that indicates a number and a location of characters and numeric strings within a candidate abbreviation; and

a definition pattern generation process that creates from said determined character strings one or more definition patterns representing candidate definitions, each of the one or more definition patterns being a template that indicates a number

Art Unit: 2626

and a location of numeric strings, stopwords, prefix/headword combinations and base words within a candidate definition.

21. A system for matching one or more abbreviations and one or more definitions, comprising:

means for examining character strings and determining which character strings to be abbreviated;

means for generating from said determined character strings one or more abbreviation patterns representing candidate abbreviations, each of the one or more abbreviation patterns being a template that indicates a number and a location of characters and numeric strings within a candidate abbreviation; and

means for generating from said determined character strings one or more definition patterns representing candidate definitions, each of the one or more definition patterns being a template that indicates a number and a location of numeric strings, stopwords, prefix/headword combinations and base words within a candidate definition.

22. A method for matching one or more abbreviations and one or more definitions, comprising:

examining character strings and determining which character strings to be abbreviated;

generating from said determined character strings one or more abbreviation patterns representing candidate abbreviations, each of the one or more abbreviation

Art Unit: 2626

patterns being a template that indicates a number and a location of characters and numeric strings within a candidate abbreviation; and

generating from said determined character strings one or more definition patterns representing candidate definitions, each of the one or more definition patterns being a template that indicates a number and a location of numeric strings, stopwords, prefix/headword combinations and base words within a candidate definition.

Allowable Subject Matter

2. Claims 1-22 are allowed over prior art of record. The following is an examiner's statement of reasons for allowance: Larkey et al. (non-patent publication, already of record) disclose a method and system for extracting acronym/abbreviation by detecting if abbreviations are present in input character strings, and if so, extracting the abbreviations and associated definitions. Abbreviations and associated definitions are stored in a database for subsequent use in retrieval applications (*referring to Larkey*). Malsheen et al. (USPN 5634084, already of record) teach a method and system for expanding abbreviations/acronyms in that text of a document is checked to determine if abbreviations/acronyms are present, and if so, expanding the abbreviations/acronyms by accessing an abbreviation/acronym database (*referring to Malsheen*). Both Larkey et al. and Malsheen et al. fail to specifically disclose an abbreviation pattern generation process that creates from said determined character strings one or more abbreviation patterns representing candidate abbreviations, each of the one or more abbreviation patterns being a template that indicates a number and a location of characters and

Art Unit: 2626

numeric strings within a candidate abbreviation; and a definition pattern generation process that creates from said determined character strings one or more definition patterns representing candidate definitions, each of the one or more definition patterns being a template that indicates a number and a location of numeric strings, stopwords, prefix/headword combinations and base words within a candidate definition.

Furthermore, it would have not been obvious to one of ordinary skill in the art at the time of invention to modify Larkey et al. and/or Malsheen et al. in order to obtain the claimed invention. Therefore, claims 1-22 are allowed over prior art of record.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to HUYEN X. VO whose telephone number is (571)272-7631. The examiner can normally be reached on M-F, 9-5:30.


If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Patrick Edouard can be reached on 571-272-7603. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Art Unit: 2626

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/Huyen X Vo/
Primary Examiner, Art Unit 2626

10/25/2008

<div><i>Application Number</i></div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/055,279	BYRD ET AL.	
	Examiner	Art Unit	
	HUYEN X. VO	2626	